## Pentacene thin film transistors with an organic/high-k inorganic bilayer gate dielectric layer on flexible substrate

설영국<sup>1</sup>, 이상설<sup>2</sup>, 안진호<sup>2</sup>, 이내응<sup>1</sup>
<sup>1</sup>성균관대학교 신소재공학과, <sup>2</sup>한양대학교 신소재공학과
\* E-mail: nelee@skku.edu

To develop the high performance OTFT devices, low threshold voltage ( $V_T$ ), low-leakage current, high current on-off ratio, and channel mobility are needed. To achieve low  $V_T$  and low-leakage current level, use of thin high-k gate dielectrics is required. For this purpose, the organic/inorganic (high-k) bilayer gate dielectric layers were investigated in this work. Flexible organic thin film transistors were fabricated using pentacene as a semiconducting layer and electroplated nickel (Ni) as a gate electrode on polyimide substrate. Electroplated gate electrode formed on the plasma-treated polyimide substrate provides a good adhesion. First, poly(4-vinyl phenol) (PVP) as an organic gate dielectric layer was deposited by spin coating after Ni gate electrode formation. Ultra-thin ( 10 nm)  $HfO_2$  as a high-k dielectric deposited by ALD (atomic layer deposition) on the spin-coated PVP layer. ALD of  $HfO_2$  layer was carried out at the substrate temperature  $220 \sim 240^{\circ}$ C. Pentacene as a semiconductor layer was thermally evaporated on the gate dielectric layer using a shadow mask in vacuum chamber at the substrate temperature of  $80^{\circ}$ C and then the thermal evaporation of gold source and drain electrodes was followed. The OTFT devices with no ALD  $HfO_2$  layer were also fabricated for comparison. The channel length varied from 10 to  $110\mu$ m, and the channel width was  $800\mu$ m. The measured I-V characteristics indicated the significant reduction in the leakage current for thinner PVP layer and improvement of current on-off ratio.